


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,325	LEE, JIAHN-LIN	
	Examiner	Art Unit	
	Tai Duong	2871	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) See search history printout	8/22/2005	TD